

## Highlights

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### Asymmetric Schottky Contacts in Bilayer MoS<sub>2</sub> Field Effect Transistors

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The high-bias electrical characteristics of back-gated field-effect transistors with chemical vapor deposition synthesized bilayer MoS<sub>2</sub> channel and Ti Schottky contacts are discussed. It is found that oxidized Ti contacts on MoS<sub>2</sub> form rectifying junctions with  $\approx 0.3$  to  $0.5$  eV Schottky barrier height. To explain the rectifying output characteristics of the transistors, a model is proposed based on two slightly asymmetric back-to-back Schottky barriers, where the highest current arises from image force barrier lowering at the electrically forced junction, while the reverse current is due to Schottky barrier-limited injection at the grounded junction. The device achieves a photoresponsivity greater than  $2.5 \text{ A W}^{-1}$  under  $5 \text{ mW cm}^{-2}$  white-LED light. By comparing two- and four-probe measurements, it is demonstrated that the hysteresis and persistent photoconductivity exhibited by the transistor are peculiarities of the MoS<sub>2</sub> channel rather than effects of the Ti/MoS<sub>2</sub> interface.

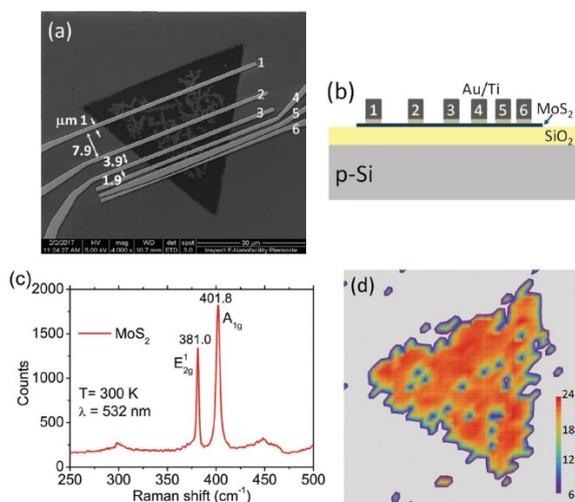


Fig. 1: a) SEM top view of a CVD-synthesized bilayer MoS<sub>2</sub> with Ti/Au contacts. b) Schematic of the back-gate transistors. c) Raman spectrum of the bilayer MoS<sub>2</sub>. d) Map of the difference between A<sub>1g</sub> and E<sub>2g</sub> peaks of micro-Raman spectra.

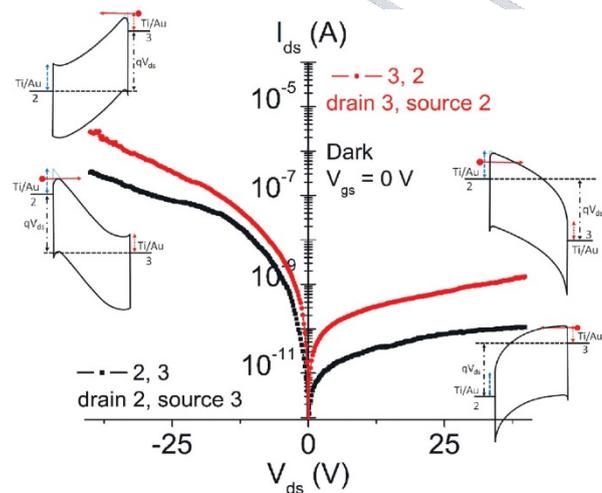


Fig. 2: Band diagram based on two back-to-back Schottky barriers. The forward current for negative  $V_{ds}$  is due to the image force barrier lowering at the forced junction, while the lower (reverse) current at  $V_{ds} > 0$  V is limited by the low electric field at the grounded junction.